

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L16	1	(enlarg\$3 and pattern and expos\$4 and mask and space and resiz\$3). clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:37

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	573	( ((second third) with (\$mask (photo adj mask) reticle)) same (mask photomask (photo adj mask) reticle) with (align\$5 overlay (over adj lay\$3))) and ((enlarg\$3 grow\$3 stretch\$3) with (pattern)) and @ad<"20040325"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 09:45
L5	81	( ((enlarg\$3 resiz\$3 (siz\$3 near2 (fix\$3 correct\$3)) increas\$3 amplif\$8 magnif\$8) near5 (lin\$3 pattern layout margin "cd" (critical near (dimension measurement features)) thin fine width\$3 spac\$3 feature)) ) and ( (proximity near5 (effect\$3 correct\$4)) or ope or ppc ) and ( (opc (optical with (correct\$3 effect\$3))) ) and ( (first primary initial) near2 (photomask (photo adj (mask reticle)) mask reticle) ) and ( ((complementary trim\$4 (multi adj phase near transistion)) near2 mask) ) and ( (reduc\$5 decreas\$3 shrink\$3 diminish\$3 lessen\$3 truncat\$5 cutback) with (width pitch densit\$3 spac\$3 ) ) and ( ( (proximity near5 (effect\$3 correct\$4)) or ope or ppc ) same (photomask (photo adj (mask reticle)) mask reticle) ) and ( (photomask (photo adj (mask reticle)) mask reticle) same ( (opc (optical with (correct\$3 effect\$3))) ) )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 09:52

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L6	420	( ((enlarg\$3 resizing\$3 (re adj sizing\$3) increase\$3 augment\$5 amplify\$8 magnify\$8) with (line\$3 margin cd (critical near\$3 (dimension measurement features)) thin fine width\$3 spacing\$3 density\$3 feature)) ) and ( (proximity near\$5 (effect\$3 correct\$4)) or open or ppc ) and ( (opc (optical with (correct\$3 effect\$3))) ) and ( (first primary initial) near\$4 (photomask (photo adj (mask reticle)) mask reticle) ) and ( ((second trim\$4 (multi adj phase near transistion)) near\$4 mask) ) and ( (reduce\$5 decrease\$3 shrink\$3 diminish\$3 lessen\$3 truncate\$5 cutback) with (width pitch density\$3 spacing\$3 cd (critical near\$3 (dimension\$3 measurement feature)) ) )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:06
L7	3	( ((mask pattern exposure reticle) near data) with (resizing\$3 enlarging\$3 (re adj sizing\$3)) ) and (opc (optical with proximity with correction)) and ( (reduce\$5 decrease\$3 shrink\$3 diminish\$3 lessen\$3 truncate\$5 cutback) near\$5 (width pitch density spacing\$3) with pattern )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:07
L8	151	( ((enlarging\$3 resizing\$3 (re adj sizing\$3) increase\$3 expand\$3 broaden\$3 add\$3 augment\$5 expansion maximize maximum grow\$3 stretch\$3 amplify magnify\$8) with pattern with (line\$3 margin thin fine width\$3 spacing\$3 density\$3 feature)) same (rule guideline constraints parameter predetermined (guide adj line) specification requirements conditions) ) and ( (first primary initial) near\$4 (photomask (photo adj (mask reticle)) mask reticle) ) and ( ((second trim\$4 (multi adj phase near transistion)) near\$4 mask) ) and ( (opc open ret ppc (proximity near\$2 (correction effect)) (resolution near\$2 enhancement)) ) and ( (line\$3 with (spacing\$3 density\$3 width)) same pattern )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:29

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L9	40	( (((mask pattern photomask (photo adj mask) exposure reticle) near data) or pattern) with (resize\$3 enlarge\$3 grow\$3 stretch\$3 increase\$3 magnify\$8 large\$3) ) and (pattern with (transfer\$5 exposure\$5)) and (first with (\$5mask (photo adj (mask reticle)) reticle) with (width density\$3 pitch space\$3)) and (second with (\$5mask (photo adj (mask reticle)) reticle) with (correspond\$5 align\$5 equivalence\$3 complementary matching overlay\$3 (over adj lay\$3) ) with (first with (\$5mask (photo adj (mask reticle)) reticle)) ) and (pattern with (rules specification constraint margin guideline (guide adj line))) and (reduce\$5 decrease\$3 shrink\$3 diminish\$3 lessen\$3 truncate\$5 cutback) with (width pitch density\$3 space\$3) and (opc or (proximity\$3 near correct\$3) ret (enhancement with technique) (resolution with enhancement) )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:25
L10	133	( (minimum minimal min) with (space spacing width) ) and ( (enlarge\$4 grow\$3 stretch\$3) with (pattern mask photomask (photo adj mask)) ) and (align\$5 overlay\$3 (over adj lay\$3)) and (mask with set) and ( (select\$3 with exposure\$5) )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:28

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L11	20	( (((mask pattern photomask (photo adj mask) exposure reticle) near data) or pattern) with (resiz\$3 enlarg\$3 grow\$3 stretch\$3 increas\$3 magnif\$8 larg\$3) ) and (pattern with (transfer\$5 expos\$5)) and (first with (\$5mask (photo adj (mask reticle)) reticle) with (width densit\$3 pitch spac\$3)) and (second with (\$5mask (photo adj (mask reticle)) reticle) with (correspond\$5 align\$5 equivalen\$3 complementary matching overlay\$3 (over adj lay\$3) ) with (first with (\$5mask (photo adj (mask reticle)) reticle)) ) and (pattern with (rules specification constraint margin guideline (guide adj line))) and (reduc\$5 decreas\$3 shrink\$3 diminish\$3 lessen\$3 truncat\$5 cutback) with (width pitch densit\$3 spac\$3) and (opc or (proximit\$3 near correct\$3) ret (enhancement with technique) (resolution with enhancement) ) and @ad<"20040325"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:27
L12	115	( (minimum minimal min) with (space spacing width) ) and ( (enlarge\$4 grow\$3 stretch\$3) with (pattern mask photomask (photo adj mask)) ) and (align\$5 overlay\$3 (over adj lay\$3)) and (mask with set) and ( (select\$3 with expos\$5) ) and @ad<"20040325"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:28
L13	90	( ((enlarg\$3 resizing\$3 (re adj siz\$3) increas\$3 expand\$3 broaden\$3 add\$3 augment\$5 expansion maximize maximum grow\$3 stretch\$3 amplify magnif\$8) with pattern with (lin\$3 margin thin fine width\$3 spac\$3 densit\$3 feature)) same (rule guideline constraints parameter predetermined (guide adj line) specification requirements conditions) ) and ( (first primary initial) near4 (photomask (photo adj (mask reticle)) mask reticle) ) and ( ((second trim\$4 (multi adj phase near transistion)) near4 mask) ) and ( (opc ope ret ppc (proximity near2 (correction effect)) (resolution near2 enhancement)) ) and ( (lin\$3 with (spac\$3 densit\$3 width)) same pattern) ) and @ad<"20040325"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/13 10:32